

**QUALIFICATION PLAN #10524**

TEST	SPECIFICATION	SAMPLE SIZE	EXPECTED COMPLETION DATE
High Temperature Operating Life (HTOL)*	JEDEC <i>JESD22-A108</i>	1*77	Nov 2013
		1*77	Nov 2013
Early Life Failure (ELF)	MIL-STD-883, <i>Method 1015</i>	3*667	Nov 2013
High Temperature Storage Life (HTSL)	JEDEC <i>JESD22-A103</i>	1*45	Oct 2013
		1*45	Oct 2013
Latch-Up	JEDEC <i>JESD78</i>	6	Oct 2013
		6	Oct 2013
Electrostatic Discharge <i>Human Body Model</i>	ESDA/JEDEC <i>JDS-001-2011</i>	3/voltage	Oct 2013
		3/voltage	Oct 2013
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JESD22-C101</i>	3/voltage	Oct 2013
		3/voltage	Oct 2013
Electrostatic Discharge <i>Machine Model</i>	JEDEC <i>JESD22-A115</i>	3/voltage	Oct 2013
		3/voltage	Oct 2013
Electrostatic Discharge <i>15kV IEC HBM</i>	IEC <i>6100-4-2</i>	3/voltage	Nov 2013
		3/voltage	

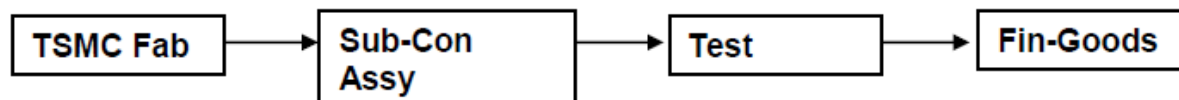
\*Preconditioned per JEDEC/IPC J-STD-020



# PCN 13\_0236:

Alternate fab source for RS-232 Transceiver products.  
To enable additional wafer fabrication capacity.

Current Flow:



Alternate Flow:

